


<b>Form 1449 (Modified)</b>  <b>Information Disclosure Statement By Applicant</b>  (Use Several Sheets if Necessary)		Atty Docket No. <b>SAY1P004</b> Applicant: <b>Michel Sayag</b> Filing Date <b>June 21, 2001</b>	Application No.: <b>09/887,543</b>  Group <b>Unknown</b>
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**U.S. Patent Documents**

Examiner Initial	No.	Patent No.	Date	Patentee	Class	Sub- class	Filing Date
CH	A1	RE. 31,847	03/12/85	Luckey	250	327.2	12/05/83
CH	A2	3,544,713	12/01/70	Tarzana et al	250	211	09/03/68
CH	A3	3,859,527	01/07/75	Luckey	250	327	01/02/73
CH	A4	4,236,168	11/25/80	Herbst	357	24	02/26/79
CH	A5	4,258,264	03/24/81	Kotera, et al	250	484	07/12/79
CH	A6	4,302,671	11/24/81	Kato, et al	250	327.1	09/28/79
CH	A7	4,364,039	12/14/82	Penz	340	784	07/25/80
CH	A8	4,373,167	02/08/83	Yamada	357	24	10/09/80
CH	A9	4,527,060	07/02/85	Suzuki, et al	250	327.2	10/18/82
CH	A10	4,679,089	07/07/87	Kato	358	213.19	02/11/86
CH	A11	4,703,177	10/27/87	Vieth	250	327	01/17/86
CH	A12	4,762,998	08/09/88	Lubinsky, et al	250	327.2	05/12/87
CH	A13	4,816,679	03/28/89	Sunagawa, et al	250	327.2	05/07/85
CH	A14	4,827,136	05/02/89	Bishop, et al	250	484.1	11/27/87
CH	A15	4,880,987	11/14/89	Hosoi, et al	250	484.1	07/22/88
CH	A16	4,887,139	12/12/89	Komastu	357	30	12/17/87
CH	A17	4,922,103	05/01/90	Kawajiri, et al	250	327.2	11/19/84
CH	A18	4,933,558	06/12/90	Carter, et al	250	327.2	01/31/89
CH	A19	4,950,895	08/21/90	Reinfelder	250	327.2	08/24/89
CH	A20	4,953,038	08/28/90	Schiebel, et al	358	471	08/25/88
CH	A21	4,977,584	12/11/90	Kohno, et al	377	58	10/23/89
CH	A22	4,983,834	01/08/91	Lindmayer, et al	250	327.2	06/07/88
CH	A23	5,017,782	05/21/91	Nelson	250	327.2	03/02/88
CH	A24	5,059,795	10/22/91	Izumi	250	327.2	08/23/90
CH	A25	5,065,866	11/19/91	Boutet, et al	206	455	11/21/90
CH	A26	5,084,619	01/28/92	Pfeiler, et al	250	327.2	07/31/91
CH	A27	5,208,459	05/04/93	Morrone, et al	250	327.2	10/03/91
CH	A28	5,266,803	11/30/93	Heffelfinger	250	582	03/03/91
CH	A29	5,268,569	12/07/93	Nelson, et al	250	214	12/31/92
CH	A30	5,299,039	03/29/94	Bohannon	359	5	03/08/91
Examiner <b>CONSTANTINE HANNAHER</b>				Date Considered	<b>DEC 15 2003</b>		

Examiner: Initial citation considered. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.



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	Applicant: <b>Michel Sayag</b>	
	Filing Date <b>June 21, 2001</b>	Group <b>Unknown</b>

### U.S. Patent Documents

Examiner Initial	No.	Patent No.	Date	Patentee	Class	Sub-class	Filing Date
CH	A31	5,396,081	03/07/95	Orgura, et al	250	585	02/15/94
CH	A32	5,455,428	10/03/95	Miyagawa,	250	586	06/08/93
CH	A33	5,483,357	01/09/96	Nagano	358	483	04/26/94
CH	A34	5,528,050	06/18/96	Miller, et al	250	585	07/24/95
CH	A35	5,563,414	10/08/96	Sklebitz	250	368	10/13/95
CH	A36	5,598,008	01/28/97	Livoni	250	586	10/18/95
CH	A37	5,715,292	02/03/98	Sayag, et al	378	98.8	11/25/94
CH	A38	5,747,825	05/05/98	Gilblom, et al	250	586	11/20/92
CH	A39	5,753,932	05/19/98	Aarkawa,	250	586	04/25/97
CH	A40	5,796,113	08/18/98	Nagli, et al	250	483.1	10/03/96
CH	A41	5,898,184	04/27/99	Stahl, et al	250	584	07/16/97
CH	A42	5,939,728	08/17/99	Wachtel, et al	250	586	04/22/97
CH	A43	5,965,897	10/12/99	Elkind, et al	250	585	02/05/98
CH	A44	5,978,026	11/02/99	Tanigawa, et al	348	311	04/28/93
CH	A45	5,981,953	11/09/99	Schoeters	250	385.1	12/04/97
CH	A46	5,998,802	12/07/99	Struye, et al	250	584	01/29/98
CH	A47	6,140,663	10/31/00	Neary, et al	250	588	03/25/98

### Foreign Patent or Published Foreign Patent Application

Examiner Initial	No.	Document No.	Publication Date	Country or Patent Office	Class	Sub-class	Translation	
							Yes	No
CH	B1	DE19946736	05/31/01	Germany				X
CH	B2	DE19922345	11/30/00	Germany				X
CH	B3	DE19946743	11/23/00	Germany				X
CH	B4	DE19859747	02/24/00	Germany				X
CH	B5	DE19962775	03/15/01	Germany				X
CH	B6	EP1054268	11/22/00	EPO			X	
CH	B7	EP1096508 A2	05/02/01	EPO			X	
CH	B8	EP1103846 A1	05/03/01	EPO			X	
CH	B9	EP0964269 A2	12/15/99	EPO			X	
Examiner <b>CONSTANTINE HANNAHER</b>				Date Considered <b>DEC 15 2003</b>				

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	Applicant: <b>Michel Sayag</b>	
	Filing Date <b>June 21, 2001</b>	Group <b>Unknown</b>

**Foreign Patent or Published Foreign Patent Application**

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							Yes	No
CH	B10	EP1081507 A2	03/07/01	EPO				X
CH	B11	EP1065525 A2	01/03/01	EPO			X	
CH	B12	EP1065526 A2	01/03/01	EPO			X	
CH	B13	EP1063505 A1	12/27/00	EPO			X	
CH	B14	EP1065671 A1	01/03/01	EPO			X	
CH	B15	EP1065523 A2	01/03/01	EPO			X	
CH	B16	EP0777148 A1	06/04/97	EPO			X	
CH	B17	EP1065527 A2	01/03/01	EPO			X	
CH	B18	EP1039338 A2	09/29/00	EPO			X	
CH	B19	EP1065524 A2	01/03/01	EPO			X	
CH	B20	EP1065528 A2	01/03/01	EPO			X	
CH	B21	EP0862066 A1	09/02/98	EPO			X	
CH	B22	EP0846962 A1	06/10/98	EPO			X	
CH	B23	EP1001276 A1	05/17/00	EPO			X	
CH	B24	EP1014684 A2	06/28/00	EPO				X
	B25	EP1037071	09/20/00	EPO			X	
		Abstract						
	B26	JP11352616	12/24/99	Japan				
		Abstract						
	B27	JP2-2955	01/07/00	Japan				
	B28	JP2-66316	03/03/00	Japan			X	
	B29	JP2-102218	01/04/00	Japan				X
	B30	JP2-29153	01/28/00	Japan				X
	B31	JP2-10217	01/04/00	Japan				X
	B32	FR2519179	07/01/83	France				X
CH	B33	WO 99/28765	06/10/99	WIPO				X
	B34	PCT/EP98/07570	06/10/99	WIPO			X	
		(claims) ?????						
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	Applicant: <b>Michel Sayag</b>	
	Filing Date <b>June 21, 2001</b>	Group <b>Unknown</b>

**Other Documents**

Examiner Initial	No.	Author, Title, Date, Place (e.g. Journal) of Publication
	C1	IEC, "Cassettes For Medical X-Ray Diagnosis Radiographic Cassettes And Mammographic Cassettes", CEI/IEC 60406 3 <sup>rd</sup> Ed., 1997
	C2	M. Thomas, "The Quantum Efficiency Of Radiographic Imaging With Image Plates" April 11, 1996, Elsevier Science B.V., pp. 599-611,
	C3	M. Thomas, <i>Image Properties Of Polycrystalline Storage Films</i> ", July 1 1996, Applied Optics Vol. 35, No. 19, pp. 3702-3714
	C4	Satoh, et al, "High-Luminance Florescent Screen With Interference Filter", SPIE Vol. 2432 July 1995, pp.462-469
	C5	
	C6	
	C7	
Examiner	<b>CONSTANTINE HANNAHER</b>	
	Date Considered	<b>DEC 15 2003</b>

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**U.S. Patent Documents or Published U.S. Patent Applications**

Examiner Initial	No.	Patent No./Pub. No.	Date	Patentee/Applicant	Class	Sub-class	Filing Date
CH	A1	US 2001/0006222	7/5/01	Gebele et al.	250	584	12/12/00
CH	A2	US 2001/0028047	10/11/01	Isoda	250	586	4/3/01
CH	A3	6,310,357 B1	10/30/01	Fuchs et al.	250	587	5/11/00
CH	A4	6,271,536 B1	8/7/01	Buytaert et al.	250	584	10/8/98

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**Foreign Patent or Published Foreign Patent Application**

Examiner Initial	No.	Document No.	Publication Date	Country or Patent Office	Class	Sub-class	Translation	
CH	B1	WO 01/48513 A2	5/7/01	WIPO (Abstract)	G01T	1/29	X	
CH	B2	EP1130417A1	5/9/01	EPO	G01T	1/29	X	

**Other Documents**

Examiner Initial	No.	Author, Title, Date, Place (e.g. Journal) of Publication
Examiner	Date Considered	
<b>CONSTANTINE HANNAHER</b>	DEC 15 2003	

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**Form 1449 (Modified)**

**Information Disclosure  
Statement By Applicant**

(Use Several Sheets if Necessary)

Atty Docket No.

SAY1P004

Applicant:

Sayag

Filing Date

6/21/01

Application No.:

09/887,543

Group

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**U.S. Patent Documents**

Examiner Initial	No.	Patent No.	Date	Patentee	Class	Sub- class	Filing Date
HA	A1	5,864,146	1/26/99	Karellas	250	581	11/13/96

**Foreign Patent or Published Foreign Patent Application**

Examiner Initial	No.	Document No.	Publication Date	Country or Patent Office	Class	Sub- class	Translation Yes No

**Other Documents**

Examiner Initial	No.	Author, Title, Date, Place (e.g. Journal) of Publication
Examiner	<b>CONSTANTINE HANNAHER</b>	
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